

150V N-Channel Enhancement Mode MOSFET

Description

The AP300N15TLG1 uses advanced **APM-SGT₁** technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 10V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 150V$ $I_D = 300A$

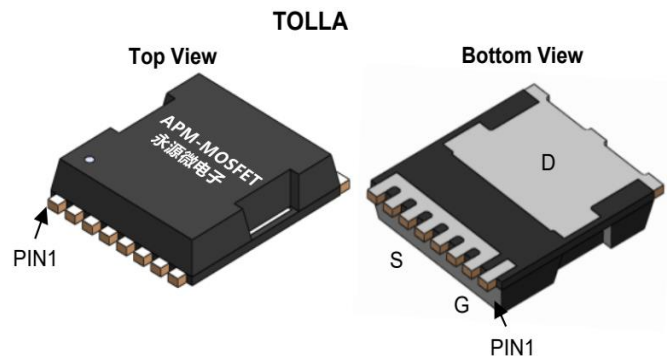
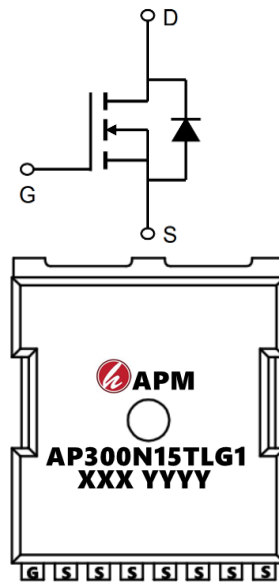
$R_{DS(ON)} < 4.2m\Omega$ @ $V_{GS}=10V$ (Type: **3.3mΩ**)

Application

DC/DC Converter

LED Backlighting

Power Management Switches



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP300N15TLG1	TOLLA-8L	AP300N15TLG1 XXX YYYY	2000

Absolute Maximum Ratings ($T_C=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	150	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D@T_C=25^{\circ}C$	Continuous Drain Current, V_{GS} @ 10V	300	A
$I_D@T_C=100^{\circ}C$	Continuous Drain Current, V_{GS} @ 10V	188	A
IDM	Pulsed Drain Current	817	A
EAS	Single Pulse Avalanche Energy	2201	mJ
IAS	Avalanche Current	88	A
$P_D@T_C=25^{\circ}C$	Total Power Dissipation ⁴	600	W
TSTG	Storage Temperature Range	-55 to 150	$^{\circ}C$
T_J	Operating Junction Temperature Range	-55 to 150	$^{\circ}C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient	0.25	$^{\circ}C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case	40	$^{\circ}C/W$

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Electrical Characteristics (T_c=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} = 0V I _D = 250μA	150	165		V
IDSS	Zero Gate Voltage Drain Current	V _{DS} = 150V, V _{GS} = 0V			1.0	nA
IDSS T _J = 55°C	Zero Gate Voltage Drain Current	V _{DS} = 150V, T _J = 55°C			5.0	
IGSS	Gate-Body Leakage Current	V _{DS} = 0V, V _{GS} = ±20V			±100	nA
VGS(th)	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	2.5	3.2	4.5	V
RDS(ON)	Static Drain-Source	V _{GS} = 10V, I _D =40A		3.3	4.2	mΩ
gFS	Forward Transconductance	V _{DS} = 5V, I _D = 20A		65		S
R _g	Gate Resistance	V _{GS} = 0V, V _{DS} = 0V, f = 1MHz		2.4		Ω
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =25V, f=1MHz		6540		pF
C _{oss}	Output Capacitance			772		pF
C _{rss}	Reverse Transfer Capacitance			6.7		pF
Q _g	Total Gate Charge	V _{GS} = 0 to 10V V _{DS} = 75V, I _D = 20A		88		nC
Q _{gs}	Gate Source Charge			32		nC
Q _{gd}	Gate Drain Charge			16		nC
tD(on)	Turn-On DelayTime	V _{GS} = 10V, V _{DS} = 75V R _L = 3.75 Ω , R _{GEN} = 6Ω		48		ns
t _r	Turn-On Rise Time			90		ns
tD(off)	Turn-Off DelayTime			94		ns
t _f	Turn-Off Fall Time			60		ns
trr	Body Diode Reverse Recovery Time	I _F =20A, dI/dt=500A/μs		122		ns
Q _{rr}	Body Diode Reverse Recovery Charge	I _F =20A, dI/dt=500A/μs		279		nC
V _{SD}	Diode Forward Voltage	I _S = 1A, V _{GS} = 0V		0.71	1.0	V
I _S	Diode Continuous Current	T _C = 25°C			600	A

Notes:

- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3、The EAS data shows Max. rating . The test condition is V_{DD}=50V, V_{GS}=10V, L=0.1mH, I_{AS}=88A
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

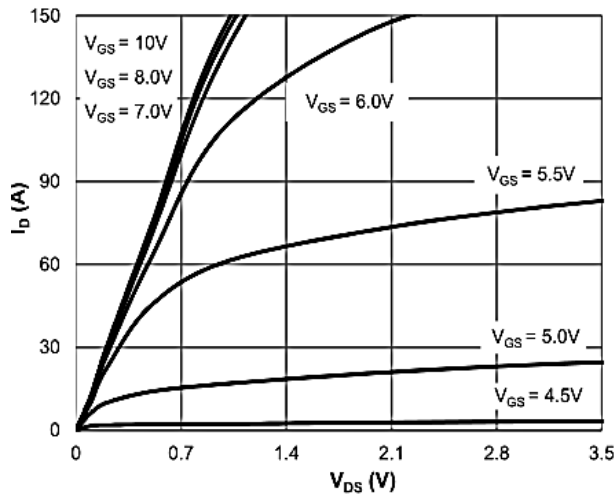


Figure 1: Saturation Characteristics

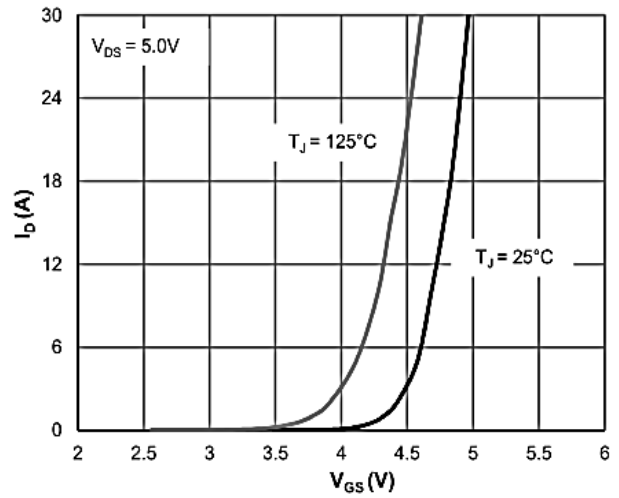


Figure 2: Transfer Characteristics

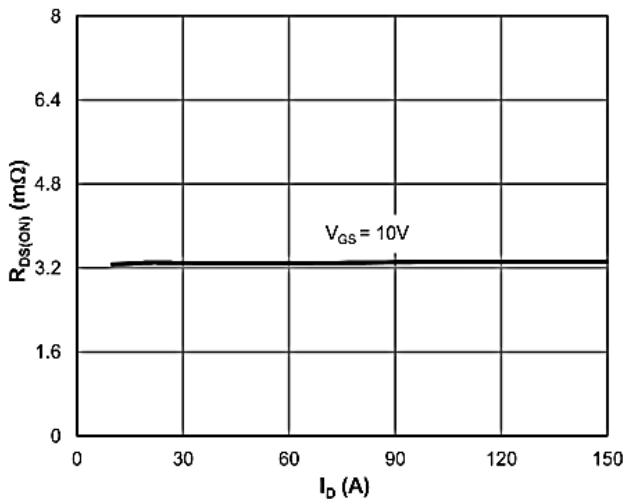


Figure 3: $R_{DS(ON)}$ vs. Drain Current

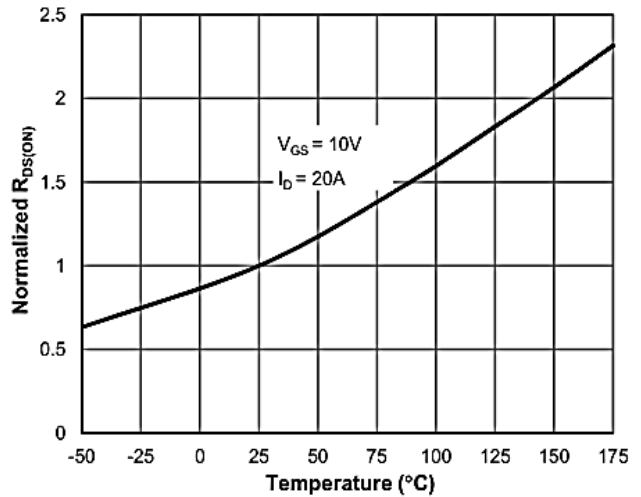


Figure 4: $R_{DS(ON)}$ vs. Junction Temperature

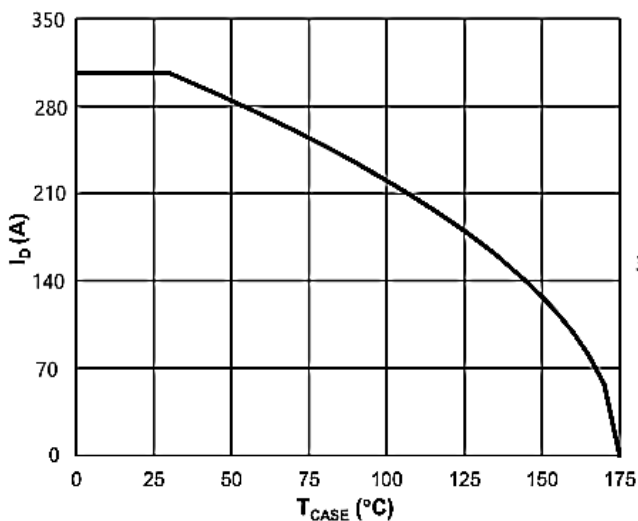


Figure 5: Current De-rating

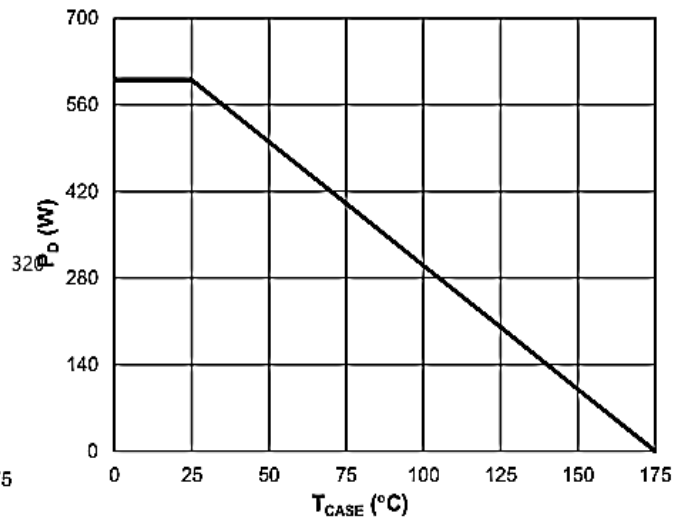


Figure 6: Power De-rating

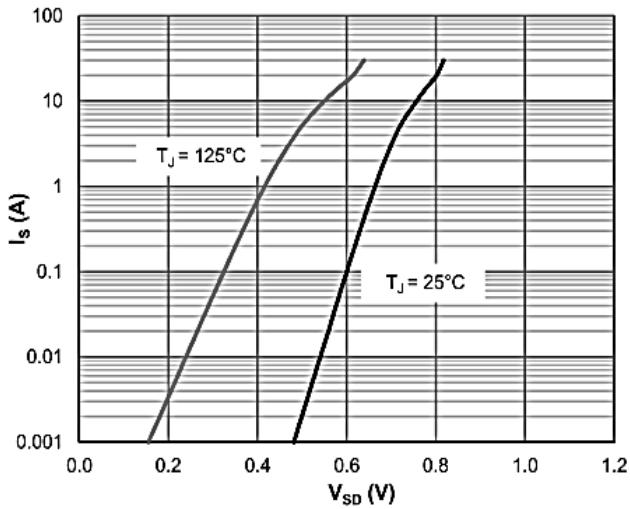


Figure 7: Body-Diode Characteristics

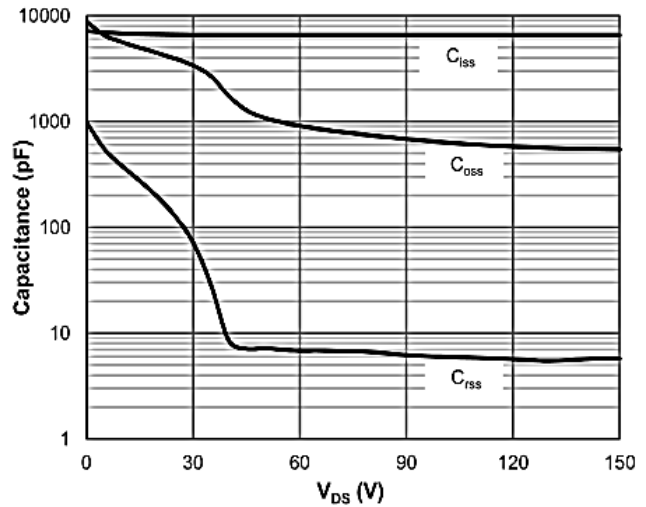


Figure 8: Capacitance Characteristics

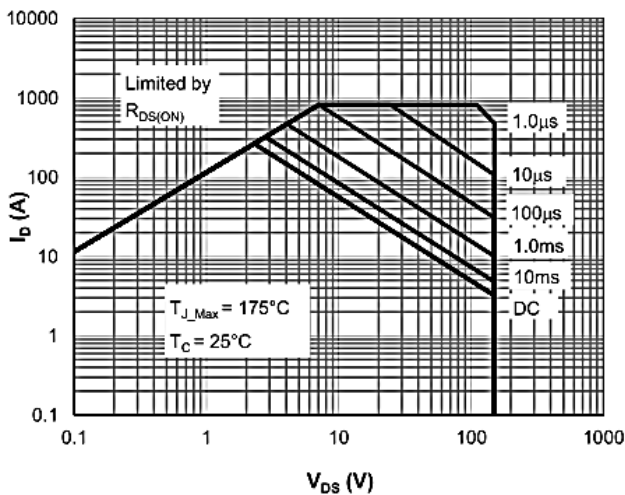


Figure 9: Maximum Safe Operating Area

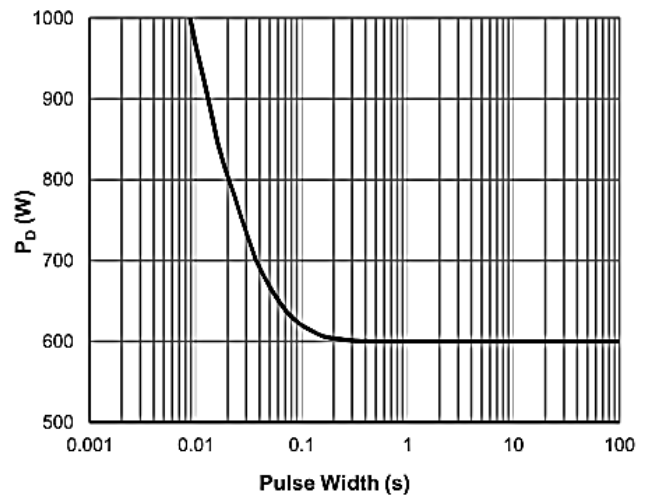


Figure 10: Single Pulse Power Rating, Junction-to-Case

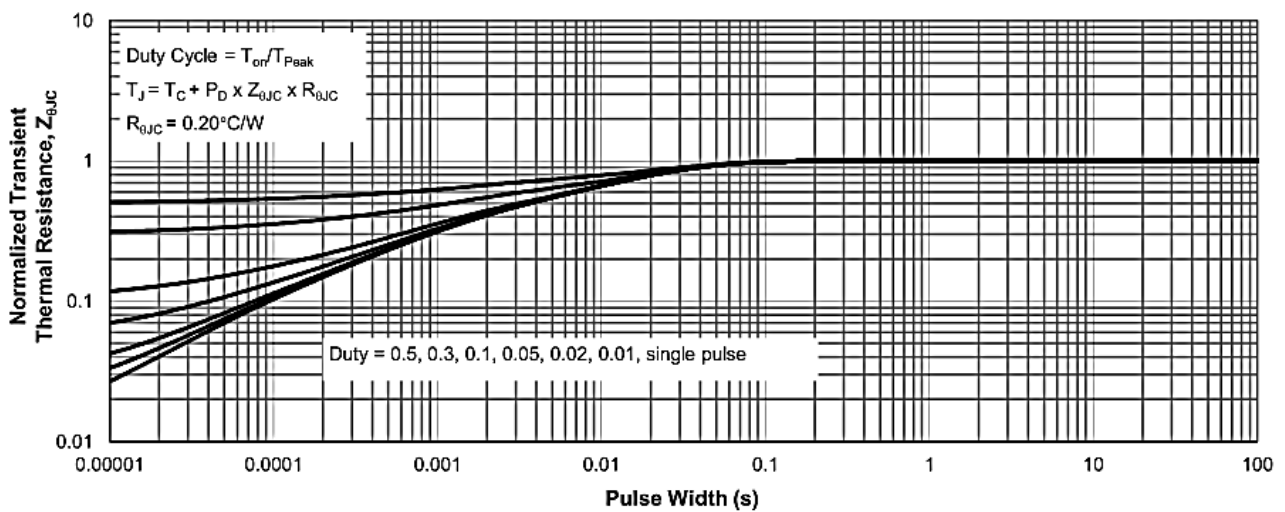
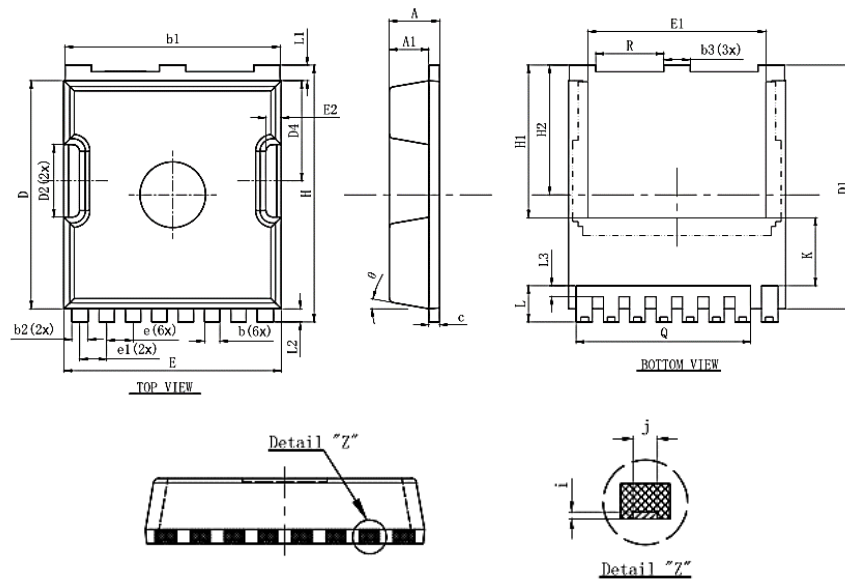


Figure 11: Normalized Maximum Transient Thermal Impedance

Package Mechanical Data-TOLLA-8-XZ Single



Symbol	Dimensions In Millimeters		
	Min.	Nom	Max.
A	2.2	2.3	2.4
A1	1.7	1.8	1.9
b	0.6	0.7	0.8
b1	9.7	9.8	9.9
b2	0.65	0.75	0.85
b3	1.1	1.2	1.3
C	0.4	0.5	0.6
D	10.3	10.4	10.5
D1	11.0	11.1	11.2
D2	3.2	3.3	3.4
D4	4.47	4.57	4.67
E	9.8	9.9	10.0
E1	8.0	8.1	8.2
E2	0.5	0.6	0.7
e	1.200 (BSC)		
e1	1.225 (BSC)		
H	11.6	11.7	11.8
H1	6.95BSC		
H2	5.9BSC		
i	0.1REF		
j	0.350REF		
K	3.100REF		
L	1.55	1.65	1.75
L1	0.6	0.7	0.8
L2	0.5	0.6	0.7
L3	0.4	0.5	0.6
Q	7.95REF		
R	3.0	3.1	3.2
θ	10°REG		

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Edition	Date	Change
REV1.0	2023/3/5	Initial release

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